

Physics of Semiconductor: Lecture # Lec 5

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What we have learnt earlier

Intrinsic semiconductor- Calculation of electron density

$$n = \int_{E_C}^{\infty} Z(E) f(E) dE$$

The above equation is the expression for the **electron concentration** in the conduction band of an intrinsic semiconductor.

Designating

$$N_C = 2 \left[\frac{2\pi m_e^* kT}{h^2} \right]^{3/2} \quad (30.29)$$

$$Z(E) dE = \frac{4\pi}{h^3} (2m_e^*)^{3/2} E^{1/2} dE \quad \text{for } E > E_C.$$

$$f(E) = \frac{1}{1 + \exp[(E - E_F) / kT]}$$

$$n = N_C e^{-(E_C - E_F)/kT} \quad (30.30)$$

N_C is a temperature dependent material constant known as the **effective density of states** in the conduction band. In silicon at 300 K, $N_C = 2.8 \times 10^{25}/\text{m}^3$.

$$n = \frac{4\pi}{h^3} (2m_e^*)^{3/2} \int_{E_C}^{\infty} (E - E_C)^{1/2} e^{-(E - E_F)/kT} dE$$

$$n = \frac{4\pi}{h^3} (2m_e^*)^{3/2} e^{(E_F - E_C)/kT} \int_{E_C}^{\infty} (E - E_C)^{1/2} e^{-(E - E_C)/kT} dE$$

$$n = 2 \left[\frac{2\pi m_e^* kT}{h^2} \right]^{3/2} e^{-(E_C - E_F)/kT}$$

Electron density available for conduction, $n = N_C e^{-(E_C - E_F)/kT}$

$$dp = Z(E)[1 - f(E)]dE \quad (30.31)$$

$$[1 - f(E)] = 1 - \frac{1}{1 + e^{(E-E_F)/kT}} = \frac{1}{1 + e^{(E_F-E)/kT}} \approx e^{-(E_F-E)/kT} \quad (30.32)$$

$$Z(E)dE = \frac{4\pi}{h^3} (2m_h^*)^{3/2} E^{1/2} dE \quad (30.33)$$

$$Z(E)dE = \frac{4\pi}{h^3} (2m_h^*)^{3/2} (E_V - E)^{1/2} dE \quad (30.34)$$

$$dp = \frac{4\pi}{h^3} (2m_h^*)^{3/2} (E_V - E)^{1/2} e^{-(E_F-E)/kT} dE \quad (30.35)$$

$$p = \frac{4\pi}{h^3} (2m_h^*)^{3/2} \int_{-\infty}^{E_V} (E_V - E)^{1/2} e^{-(E_F-E)/kT} dE \quad (30.36)$$

$$= \frac{4\pi}{h^3} (2m_h^*)^{3/2} e^{-(E_F-E_V)/kT} \int_{-\infty}^{E_V} (E_V - E)^{1/2} e^{-(E_V-E)/kT} dE \quad (30.37)$$

$$N_V = 2 \left[\frac{2\pi m_h^* kT}{h^2} \right]^{3/2}$$

$$p = N_V e^{-(E_F - E_V)/kT}$$

INTRINSIC CARRIER CONCENTRATION

$$n = p = n_i$$

$$n_i^2 = np \quad (30.42)$$

$$\begin{aligned} &= (N_C e^{-(E_C - E_F)/kT}) (N_V e^{-(E_F - E_V)/kT}) \\ &= (N_C N_V) e^{-(E_C - E_V)/kT} \end{aligned} \quad (30.43)$$

 \therefore

$$n_i^2 = (N_C N_V) e^{-E_g/kT}$$

$$= 4 \left[\frac{2\pi kT}{h^2} \right]^3 (m_e^* m_h^*)^{3/2} e^{-E_g/kT}$$

 \therefore

$$n_i = 2 \left[\frac{2\pi kT}{h^2} \right]^{3/2} (m_e^* m_h^*)^{3/4} e^{-E_g/2kT} \quad (30.45)$$

This is the expression for intrinsic carrier concentration.

FERMI LEVEL IN INTRINSIC SEMICONDUCTOR

$$n = N_C e^{-(E_C - E_F)/kT} \quad p = N_V e^{-(E_F - E_V)/kT}$$

$$N_C e^{-(E_C - E_F)/kT} = N_V e^{-(E_F - E_V)/kT}$$

$$E_F = \frac{E_C + E_V}{2} + \frac{1}{2} kT \ln \frac{N_V}{N_C}$$

$$\text{But } N_C = 2 \left[\frac{2\pi m_e^* kT}{h^2} \right]^{3/2} \text{ and } N_V = 2 \left[\frac{2\pi m_h^* kT}{h^2} \right]^{3/2}$$

If the effective mass of a free electron is assumed to be equal to the effective mass of a hole, i.e.,

$$\therefore E_F = \frac{E_C + E_V}{2} + \frac{3}{4} kT \ln \left(\frac{m_h^*}{m_e^*} \right)$$

$$\begin{aligned} m_h^* &= m_e^* \\ \ln \left(\frac{m_h^*}{m_e^*} \right) &= 0 \end{aligned}$$

\therefore

$$E_F = \frac{E_C + E_V}{2}$$

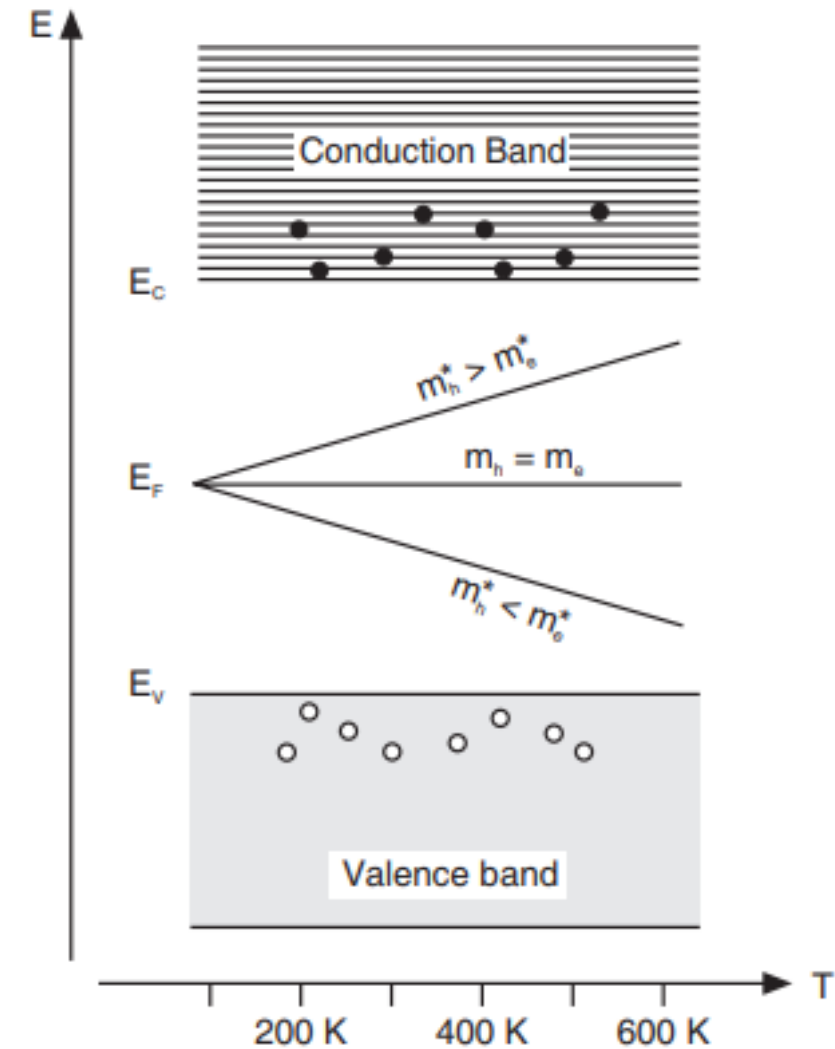
To make the meaning of the above equation more explicit, we write

$$E_F = \frac{E_C - E_V}{2} + E_V$$

$$E_F = \frac{E_g}{2} + E_V$$

If we denote the top of the valence band E_V as zero level, $E_V = 0$.

$$E_F = \frac{E_g}{2}$$

FERMI LEVEL IN INTRINSIC SEMICONDUCTOR

$$\sigma_i = ne\mu_e + pe\mu_h$$

$$= n_i e(\mu_e + \mu_h) \quad \text{as } n_i = n = p$$

$$= (\mu_e + \mu_h) e \quad 2 \left(\frac{2\pi kT}{h^2} \right)^{3/2} (m_e^* m_h^*)^{3/4} e^{-\left(E_g / 2kT \right)}$$

$$n_i = 2 \left[\frac{2\pi kT}{h^2} \right]^{3/2} (m_e^* m_h^*)^{3/4} e^{-E_g / 2kT}$$

μ_e and μ_h are determined by scattering from lattice vibrations (phonons) and has a dependence of $T^{-3/2}$, therefore temperature dependence of conductivity is determined by the exponential term only and all the rest of the terms can be accounted for as a constant A. Expression for conductivity can be then written as

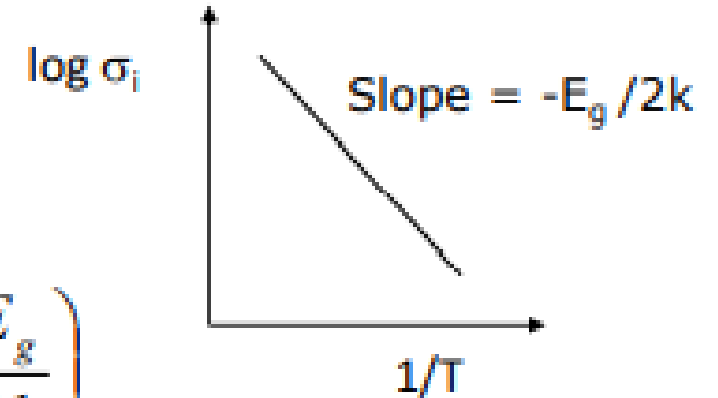
$$\sigma_i = A e^{-E_g / 2kT}$$

$$\sigma_i = Ae^{-E_g/2kT}$$

Taking log on either side

$$\log \sigma_i = \log A - \frac{E_g}{2kT}$$

$$\text{slope of } (\log \sigma) \text{ vs } (1/T) \text{ curve} = \frac{\partial(\log \sigma)}{\partial(1/T)} = 0 - \left(\frac{E_g}{2k} \right) = - \left(\frac{E_g}{2k} \right)$$



$$I/A = J = \sigma E = \sigma V/d$$

Do an experiment with a semiconductor keeping E constant (ensure that only thermally generated carriers are contributing to the current), and then heat the device. Measure change in I with temperature, you will essentially be tracking variation of σ with temperature.

Experimental determination of bandgap from R vs T variation

Resistivity, $\rho_{\text{intrinsic}} = 1/\sigma_{\text{intrinsic}} = R_i/L$, where L-length, a-Area of semiconductor

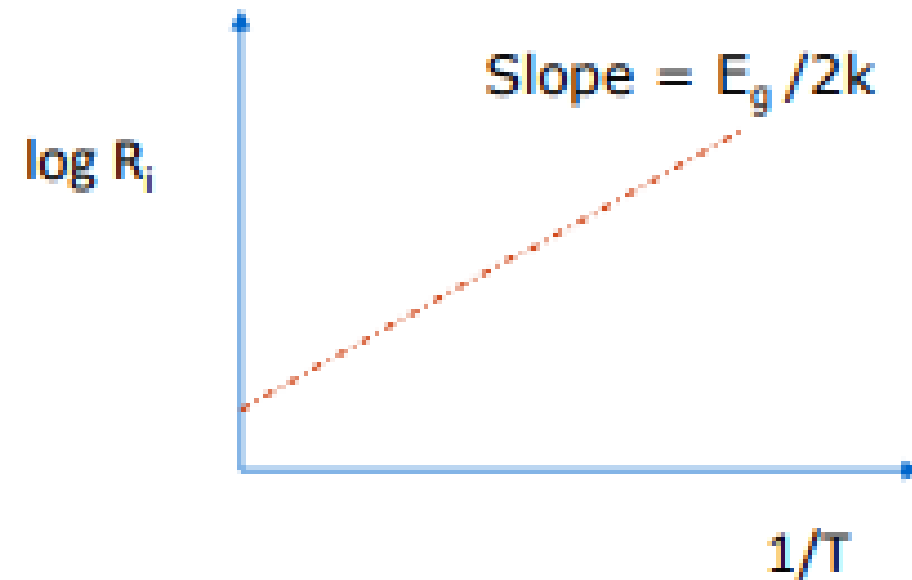
Therefore, resistance of intrinsic semiconductor

$$R_i = L/a\sigma_{\text{intrinsic}}$$

$$= \underbrace{\frac{L}{aA}}_C e^{E_g/2kT}$$

$$\log R_i = \log C + \frac{E_g}{2kT}$$

$$\sigma_i = Ae^{-E_g/2kT}$$



- ▶ Resistance R_i of a given slab of intrinsic material is measured as a function of temperature
- ▶ A graph is plotted between log of resistance in Y axis and $1/T$ in the X- axis.
- ▶ E_g is determined as ($2k \times \text{slope of line}$)

30.14 LIMITATIONS OF INTRINSIC SEMICONDUCTOR

Intrinsic semiconductors are not useful for device manufacture because of low conductivity and the strong dependence of conductivity on temperature. If we take a crystal of pure silicon or germanium and connect it in the circuit, we will find that the current in the circuit will gradually increase as the temperature of the crystal is increased. We would also expect the current to increase if the voltage is increased and it does. But *increasing the voltage increases the current only proportionally, obeying Ohm's law, while increasing the temperature increases the current at an exponential rate*. Thus the temperature over which we have no control exerts more influence upon the current than the voltage, which we customarily do control.

We summarize the limitations as follows:

- Conductivity is low. Germanium has a conductivity of 1.67 S/m, which is nearly 10^7 times smaller than that of copper.
- Conductivity is a function of temperature and increases exponentially as the temperature increases.
- Conductivity cannot be controlled from outside.

- Types of semiconductors
- (i) Intrinsic (Elemental & Compound)
 - (ii) Extrinsic

Intrinsic semiconductors are pure semiconductors characterized by completely filled valence shell at 0K ,with conductivity at higher temperatures due to thermally or optically generated electron-hole pairs .($n=p=n_i$)

Conductivity in semiconductors is due to both holes (electrons in valence band) and electrons (in conduction band)

Electron density available for conduction, $n = N_c e^{-(E_c - E_F)/kT}$

Hole density available for conduction, $p = N_v e^{-(E_F - E_v)/kT}$

Fermi level and its position as a function of temperature

$$E_F = \frac{(E_c + E_v)}{2} + \frac{3kT}{4} \ln \left(\frac{m_h^*}{m_e^*} \right)$$

OR

$$E_F = \frac{E_g}{2} + \frac{3kT}{4} \ln \left(\frac{m_h^*}{m_e^*} \right)$$

From top of valence band

Intrinsic carrier concentration and conductivity

$$\therefore n_i = \sqrt{np} = \sqrt{N_c N_v} e^{-\left(E_g / 2kT\right)} = 2 \left(\frac{2\pi kT}{h^2} \right)^{3/2} (m_e^* m_h^*)^{3/4} e^{-\left(E_g / 2kT\right)}$$

$$\sigma = (\mu_e + \mu_h) e \cdot 2 \left(\frac{2\pi kT}{h^2} \right)^{3/2} (m_e^* m_h^*)^{3/4} e^{-\left(E_g / 2kT\right)}$$

Bandgap measurement

$$\text{slope of } (\log \sigma) \text{ vs } (1/T) \text{ curve} = \frac{\partial(\log \sigma)}{\partial(1/T)} = -\left(\frac{E_g}{2k} \right)$$

Bandgap determined from experiment measuring R vs T. as (2k x slope of plot between log R & 1/T)

For Silicon with a bandgap of 1.12eV, determine position of Fermi level at 300K if $m_e^* = 0.12m_0$ and $m_h^* = 0.28m_0$

For an intrinsic semiconductor with $E_g = 0.7\text{eV}$ and carrier concentration of $33.49 \times 10^{18} / \text{m}^3$, calculate conductivity at 300K assuming $m_e^* = m_h^* = m_0$; $\mu_e = 0.39 \text{ m}^2 / \text{Vs}$, $\mu_h = 0.19 \text{ m}^2 / \text{Vs}$

Find the resistance of an intrinsic Ge slab 1cm long, 1mm wide and 1mm thick if the intrinsic carrier concentration is $2.5 \times 10^{19} / \text{m}^3$, $\mu_e = 0.39 \text{ m}^2 / \text{Vs}$, $\mu_h = 0.19 \text{ m}^2 / \text{Vs}$ at 300K

If the effective mass of holes in an intrinsic material is 4 times that of the electron, find the temperature at which the Fermi level is shifted by 10% from the middle of the forbidden gap of energy 1eV.

For Silicon with a bandgap of 1.12eV, determine position of Fermi level at 300K if $m_e^* = 0.12m_0$ and $m_h^* = 0.28m_0$

Given $E_g = 1.12\text{eV}$, $T = 300\text{K}$, $m_e^* = 0.12m_0$, $m_h^* = 0.28m_0$, position of Fermi level ?

$$E_F = \frac{E_g}{2} + \frac{3kT}{4} \ln \left(\frac{m_h^*}{m_e^*} \right) \quad \text{From top of valence band}$$

$$\begin{aligned} E_F &= \frac{1.12}{2} + \frac{3 \times 1.38 \times 10^{-23} \times 300}{4 \times 1.6 \times 10^{-19}} \ln \left(\frac{0.28}{0.12} \right) \text{ eV} \quad \text{from top of valence band} \\ &= 0.56 + 0.0164 = 0.5764 \text{ eV} \quad \text{from top of valence band} \end{aligned}$$

- ☐ A judicious introduction of impurity atoms in an otherwise perfect semiconductor crystal produces useful modifications of its electrical conductivity.
- ☐ It makes the current more voltage dependent than temperature dependent.
- ☐ An intentional introduction of controlled amount of impurity into an intrinsic semiconductor is called doping.
- ☐ The impurity added is called a dopant.
- ☐ A semiconductor doped with impurity atoms is called an extrinsic semiconductor.
- ☐ The impurity-produced electrons are not temperature-dependent but are voltage-dependent and they will be under our control.
- ☐ Typical doping levels range from 10^{20} to 10^{27} impurity atoms/m³.
- ☐ Pentavalent elements from Group V or trivalent elements from Group III are used as dopants.

110000

H

Hydrogen

Nonmetal

400200

He

Helium

Noble Gas

700

Li

Lithium

Alkali Metal

901200

Be

Beryllium

Alkaline Earth Metal

220007000

Na

Sodium

Alkali Metal

24300

Mg

Magnesium

Alkaline Earth Metal

190000

K

Potassium

Alkali Metal

4000

Ca

Calcium

Alkaline Earth Metal

85400

Rb

Rubidium

Alkali Metal

8700

Sr

Strontium

Alkaline Earth Metal

1320004000

Cs

Cesium

Alkali Metal

13700

Ba

Barium

Alkaline Earth Metal

22300070

Fr

Francium

Alkali Metal

22600000

Ra

Radium

Alkaline Earth Metal

17

35.45

Cl

Chlorine

Halogen

Plot Atomic Mass

10000

B

Boron

Metalloid

12000

C

Carbon

Nonmetal

14000

N

Nitrogen

Nonmetal

16000

O

Oxygen

Nonmetal

180004010

F

Fluorine

Halogen

260000000

Al

Aluminum

Post Transition Metal

28000

Si

Silicon

Metalloid

3000070000

P

Phosphorus

Nonmetal

3200

S

Sulfur

Nonmetal

3545

Cl

Chlorine

Halogen

3600

Ar

Argon

Noble Gas

58000

Sc

Scandium

Transition Metal

47000

Ti

Titanium

Transition Metal

50000

V

Vanadium

Transition Metal

51000

Cr

Chromium

Transition Metal

540000

Mn

Manganese

Transition Metal

5500

Fe

Iron

Transition Metal

580000

Co

Cobalt

Transition Metal

58000

Ni

Nickel

Transition Metal

6300

Cu

Copper

Transition Metal

6500

Zn

Zinc

Transition Metal

69000

Ga

Gallium

Post Transition Metal

7200

Ge

Germanium

Metalloid

740000

As

Arsenic

Metalloid

7600

Se

Selenium

Nonmetal

7900

Br

Bromine

Halogen

8300

Kr

Krypton

Noble Gas

8500

Y

Yttrium

Transition Metal

9100

Zr

Zirconium

Transition Metal

920000

Nb

Niobium

Transition Metal

9500

Mo

Molybdenum

Transition Metal

98000

Tc

Technetium

Transition Metal

1010

Ru

Ruthenium

Transition Metal

101000

Rh

Rhodium

Transition Metal

106000

Pd

Palladium

Transition Metal

107000

Ag

Silver

Transition Metal

11200

Cd

Cadmium

Transition Metal

114000

In

Indium

Post Transition Metal

11800

Sn

Tin

Post Transition Metal

121000

Sb

Antimony

Metalloid

12700

Te

Tellurium

Metalloid

126000

I

Iodine

Halogen

13100

Xe

Xenon

Noble Gas

17800

Hf

Hafnium

Transition Metal

180000

Ta

Tantalum

Transition Metal

18300

W

Tungsten

Transition Metal

186000

Re

Rhenium

Transition Metal

19000

Os

Osmium

Transition Metal

19200

Ir

Iridium

Transition Metal

19500

Pt

Platinum

Transition Metal

1960000

Au

Gold

Transition Metal

20000

Hg

Mercury

Transition Metal

204000

Tl

Thallium

Post Transition Metal

20700

Pb

Lead

Post Transition Metal

2080000

Bi

Bismuth

Post Transition Metal

2080000

Po

Polonium

Metalloid

2090000

At

Astatine

Halogen

2220000

Rn

Radon

Noble Gas

262000

Rf

Rutherfordium

Transition Metal

268000

Db

Dubnium

Transition Metal

268000

Sg

Seaborgium

Transition Metal

270000

Bh

Bohrium

Transition Metal

284000

Hs

Hassium

Transition Metal

277000

Mt

Mitnerium

Transition Metal

288000

Ds

Darmstadtium

Transition Metal

288000

Rg

Roentgenium

Transition Metal

289000

Cn

Copernicium

Transition Metal

289000

Nh

Nihonium

Post Transition Metal

289000

Fl

Flerovium

Post Transition Metal

289000

Mc

Moscovium

Post Transition Metal

289000

Lv

Livermorium

Post Transition Metal

294000

Ts

Tennesine

Halogen

294000

Og

Oganesson

Noble Gas

138000

La

Lanthanum

Lanthanide

140000

Ce

Cerium

Lanthanide

1400000

Pr

Praseodymium

Lanthanide

14400

Nd

Neodymium

Lanthanide

1440000

Pm

Promethium

Lanthanide

15000

Sm

Samarium

Lanthanide

151000

Eu

Europium

Lanthanide

15700

Gd

Gadolinium

Lanthanide

1580000

Tb

Terbium

Lanthanide

162000

Dy

Dysprosium

Lanthanide

1640000

Ho

Holmium

Lanthanide

16700

Er

Erbium

Lanthanide

1680000

Tm

Thulium

Lanthanide

17300

Yb

Ytterbium

Lanthanide

1740000

Lu

Lutetium

Lanthanide

22700000

Ac

Actinium

Actinide

232000

Th

Thorium

Actinide

231000000

Pa

Protactinium

Actinide

2380000

U

Uranium

Actinide

237000000

Np

Neptunium

Actinide

244000000

Pu

Plutonium

Actinide

243000000

Am

Americium

Actinide

247000000

Cm

Curium

Actinide

247000000

Bk

Berkelium

Actinide

251000000

Cf

Californium

Actinide

252000000

Es

Einsteinium

Actinide

257000000

Fm

Fermium

Actinide

258000000

Md

Mendelevium

Actinide

259000000

No

Nobelium

Actinide

260000000

Lr

Lawrencium

Actinide

DISPLAY PROPERTY/TREND

Chemical Group Block

- ❑ The atoms belonging to these two groups are nearly of the same size as silicon or germanium atoms and easily substitute themselves in place of some of the host atoms in the semiconductor crystal.
- ❑ Thus, they are substitutional impurities and do not cause any distortion in the original crystal structure.
- ❑ Depending on the two different types of doping, two types of extrinsic semiconductors are possible.
- ❑ They are n-type and p-type semiconductors.

Common Dopant Elements for Silicon and Germanium

n-type

Phosphorous

Arsenic

Antimony

p-type

Aluminium

Boron

Gallium

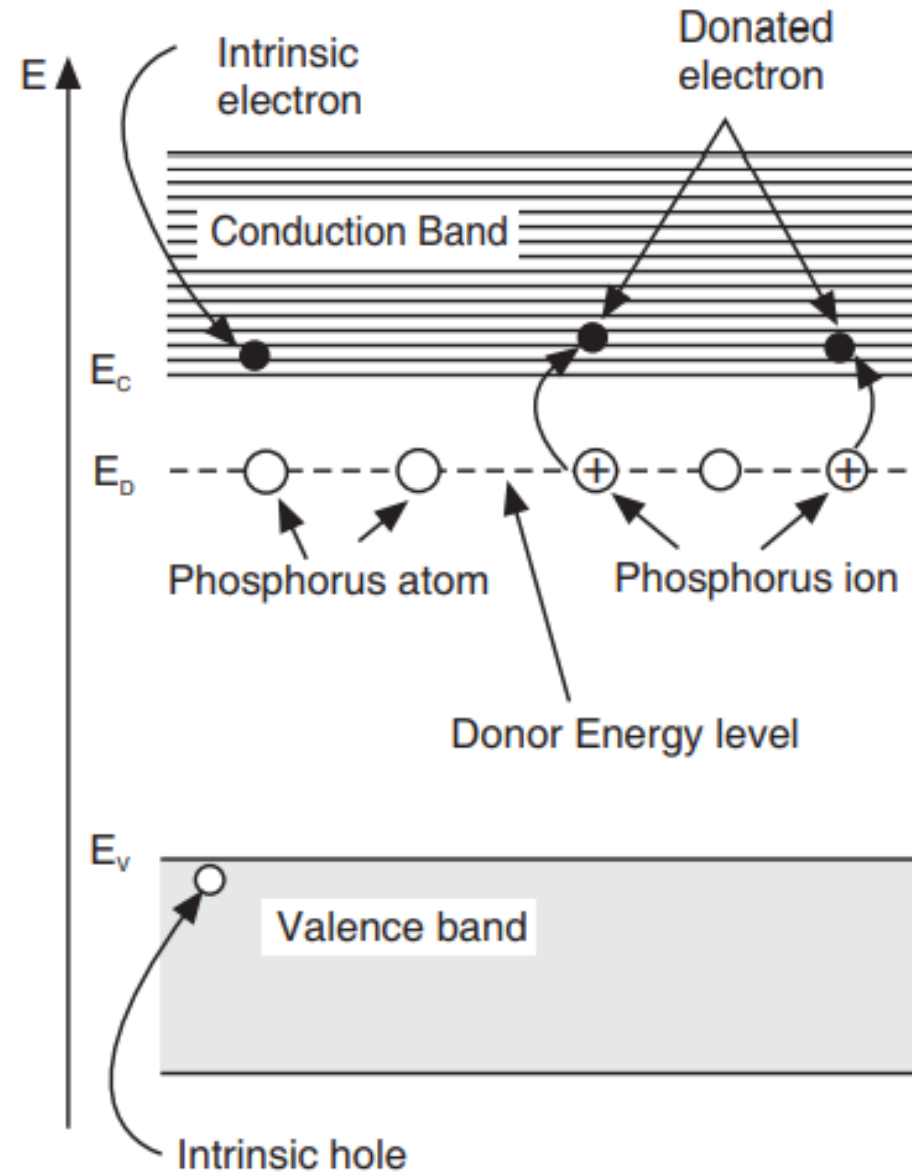
Indium

Advantages of Extrinsic Semiconductors

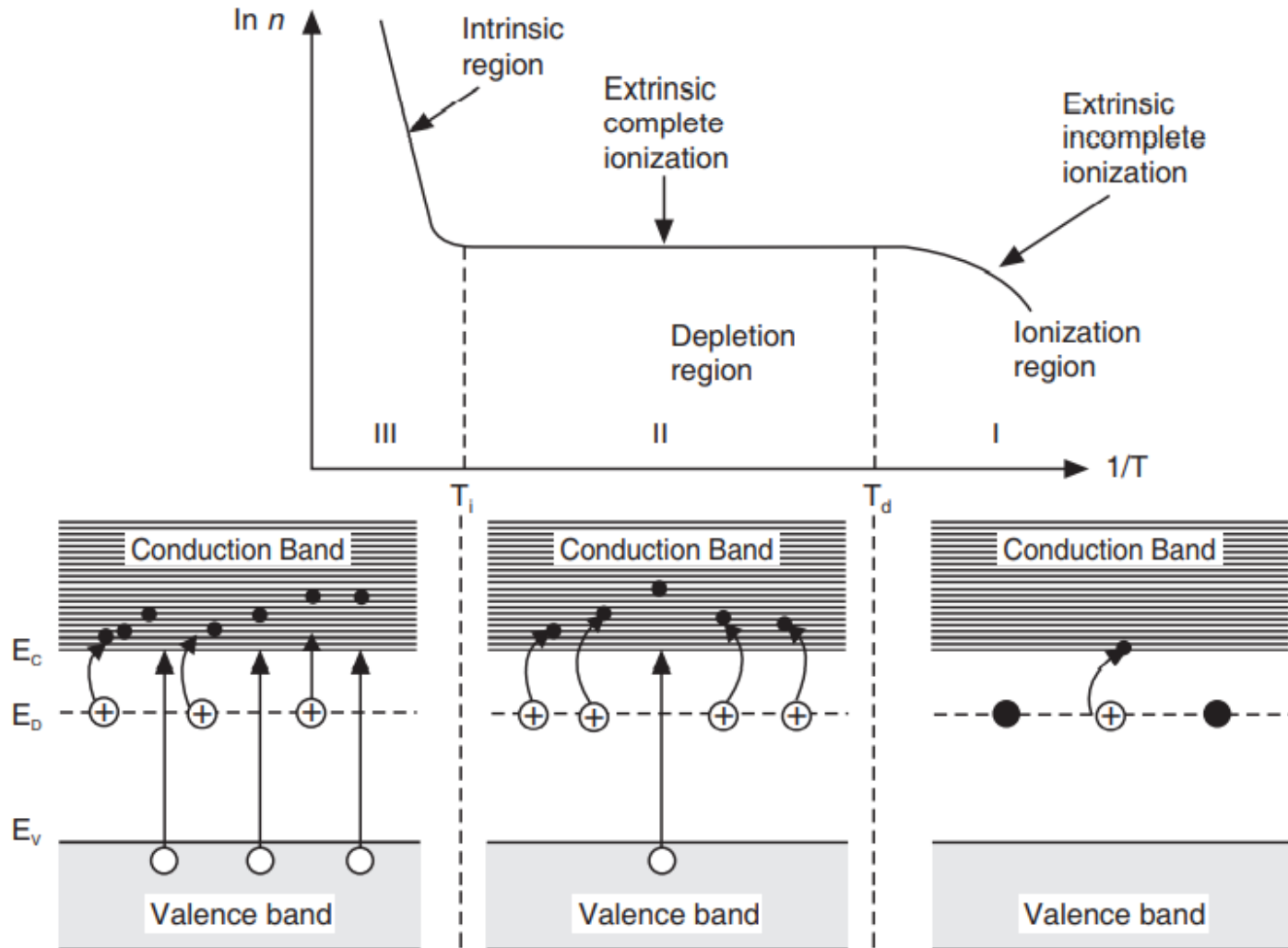
- Conductivity is high.
- Conductivity can be tailored to the desired value through the control of doping concentration.
- Conductivity is not a function of temperature.

- ☐ An n-type semiconductor is produced when a pure semiconductor is doped with a pentavalent impurity such as phosphorous.
- ☐ A phosphorous atom has five valence electrons.
- ☐ Out of the five electrons, only four participate in bonding with four host silicon atoms while the fifth electron remains loosely bound.
- ☐ The host silicon lattice is a dielectric medium having a dielectric constant of 12.
- ☐ As a result, the Coulomb force between the phosphorous nucleus and the fifth electron is smaller than that it would be in free space.
- ☐ Therefore, the ionization energy of the fifth electron is very small.
- ☐ It is found to be 0.045 eV.
- ☐ The ionization energy is so small that the thermal energy can easily liberate the fifth electron from the nucleus.

- ❑ It means that the energy levels corresponding to phosphorous atoms are nearer to the bottom edge of the conduction band.
- ❑ At normal temperatures, the fifth electron becomes free to move about in the crystal and acts as a charge carrier.
- ❑ That is, the electron jumps into the conduction band leaving behind the positive phosphorous ion that is fixed in the crystal lattice.
- ❑ As the phosphorous atom is donating an electron for the purpose of electrical conduction, it is called a donor atom.
- ❑ If the donor atom density is low, the donor atoms are distantly spaced from one another, approximately, by 100 atom spacings.
- ❑ In such a situation, the donor atoms cannot interact with each other, and their energy levels are discrete levels, E_D .
- ❑ They are called donor levels and represent the ground state of the fifth electron of impurity atom.
- ❑ As even small amount of thermal energy can readily liberate the fifth electron from the atom and send it into the conduction band, the donor levels are expected to be located very near to the bottom edge of the conduction band.



Temperature Variation of Carrier Concentration

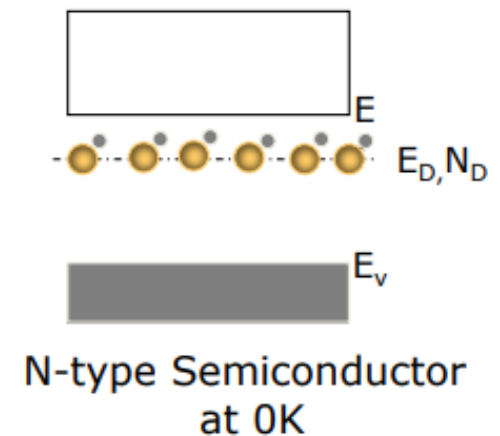
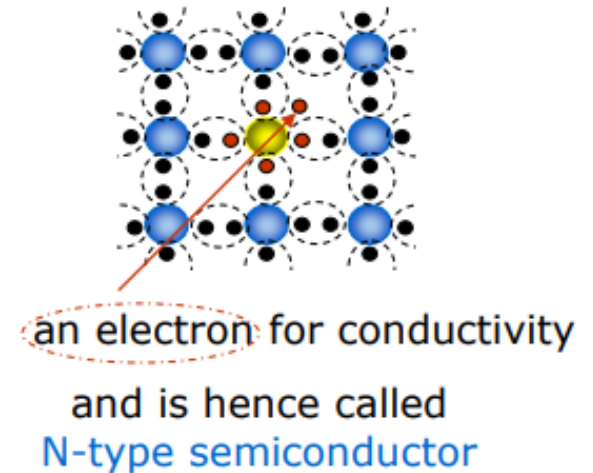


1. @ 0K
2. Then raise temperature
3. @ 100 K all donor atoms are ionized
4. @ high temperature

In n-type material the electrons outnumber the holes and constitute the majority carriers (in region II). Holes are minority carriers. The number of carriers is independent of temperature in the depletion region. The current in this type of crystal is mainly due to the negatively charged electrons and hence the material is called n-type semiconductor

- ▶ In a N type semiconductor pentavalent impurity replaces the covalently bonded host semiconductor atoms.
- ▶ Electron of the pentavalent impurity atom that is not involved in any covalent bond is loosely bound to its nucleus with small binding energies ($\sim 0.045\text{eV}$).
- ▶ This is so small that the electron, acquires this small amount of energy, and becomes "free" leaving the impurity (+vely charged) **without generation of holes in the valence band**
- ▶ The pentavalent impurity which donates electrons to the conduction band structure is called a donor.
- ▶ The ionization energy of the electron is $1/25^{\text{th}}$ of energy gap and since the donated electron occupies the conduction band it implies energy level of donor atoms are close to E_c and lesser than E_c by 0.045eV

Let the no. density of impurity atoms be N_D



Carrier Concentration in n-type Semiconductor at Low Temperatures: (In the Ionization Region)

N_D = concentration of donors in the material

@ 0K, the donor atoms are not ionized----- are at the level E_D which is very near to E_C

When temperature is raised above 0 K, the donor atoms get ionized and free electrons appear in the CB.

With increase in temperature more, more donor atoms get ionized and electron concentration in the conduction band increases

n = electron concentration in the conduction band

$$n = N_D^+$$

$$n = N_D - N_D^0$$

where N_D^+ is the number of donor atoms that are ionized and N_D^0 is the number of atoms left unionized at the energy level E_D .

The concentration of ionized donors $N_D^+ = (N_D - N_D^0) = N_D[1 - f(E_D)]$

Therefore, **at low temperatures**, no. of carriers for conduction in a N type material, n_n = no. density of electrons in conduction band
= no. of ionized impurity atoms (N_D^+)

N_D^+ = no. density of impurity atoms in the donor energy level x
probability that they are not occupied by an electron

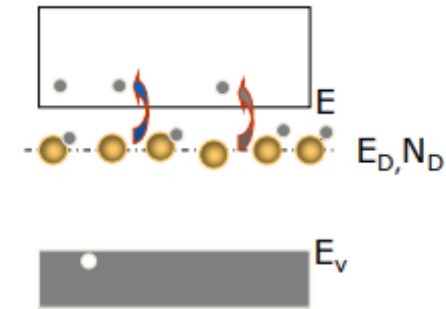
$$= N_D \times [1 - F(E_D)]$$

$$(1 - F(E_D)) = 1 - \frac{1}{1 + \exp\left(\frac{E_D - E_{Fn}}{k_B T}\right)} = \frac{1 + \exp\left(\frac{E_D - E_{Fn}}{k_B T}\right) - 1}{1 + \exp\left(\frac{E_D - E_{Fn}}{k_B T}\right)}$$

$$= \frac{1}{1 + \exp\left(\frac{E_{Fn} - E_D}{k_B T}\right)} \quad \exp\left(\frac{E_{Fn} - E_D}{k_B T}\right) \gg 1$$

$$\text{Therefore, } (1 - F(E_D)) \approx \frac{1}{\exp\left(\frac{E_{Fn} - E_D}{k_B T}\right)} \approx \exp\left(\frac{E_D - E_{Fn}}{k_B T}\right)$$

$$(n_n) = (N_D^+) = N_D(1 - F(E_D)) = N_D \exp\left(\frac{E_D - E_{Fn}}{k_B T}\right)$$



N-type Semiconductor

$$n_n = N_c \times \exp\left(\frac{E_{Fn} - E_{cn}}{k_B T}\right) = (N_D^+) = N_D \exp\left(\frac{E_D - E_{Fn}}{k_B T}\right)$$

$$\exp\left(\frac{E_{Fn} - E_{cn} - E_D + E_{Fn}}{k_B T}\right) = \frac{N_D}{N_c} \quad \exp\left(\frac{2E_{Fn} - (E_{cn} + E_D)}{k_B T}\right) = \frac{N_D}{N_c}$$

Taking natural logarithms on both sides

$$\frac{2E_{Fn} - (E_{cn} + E_D)}{k_B T} = \ln\left[\frac{N_D}{N_c}\right] \quad 2E_{Fn} - (E_{cn} + E_D) = k_B T \ln\left[\frac{N_D}{N_c}\right] \quad \therefore E_{Fn} = \frac{E_{cn} + E_D}{2} + \frac{k_B T}{2} \ln\left[\frac{N_D}{N_c}\right]$$

$$E_{Fn} = \frac{E_{cn} + E_D}{2} + \frac{k_B T}{2} \ln\left[\frac{N_D}{2 \left(\frac{2\pi m_e^* k_B T}{h^2}\right)^{3/2}}\right]$$

i.e Fermi level of N-type semiconductor lies midway between bottom of conduction band E_{cn} and the donor level, E_D at 0K and falls with temperature as $N_D/N_c < 1$ or $\ln(N_D/N_c)$ is -ve.

$$E_{Fn} = \frac{E_{cn} + E_D}{2} + \frac{k_B T}{2} \ln \left[\frac{N_D}{N_c} \right]$$

- ▶ At 0K, Fermi level of N-type semiconductor lies midway between bottom of conduction band E_c and the donor level, E_D
- ▶ As temperature increases E_{Fn} falls as $N_D/N_c < 1$ or $\ln(N_D/N_c)$ is -ve.
- ▶ Once all the donor atoms are ionized, the Fermi level falls and becomes equal to the center of the bandgap
i.e becomes equal to the Fermi level of intrinsic semiconductor, E_{Fi}
- ▶ For semiconductors doped with higher concentration of impurities, the Fermi level drops more slowly and attains E_{Fi} at relatively higher temperatures (green curve)

